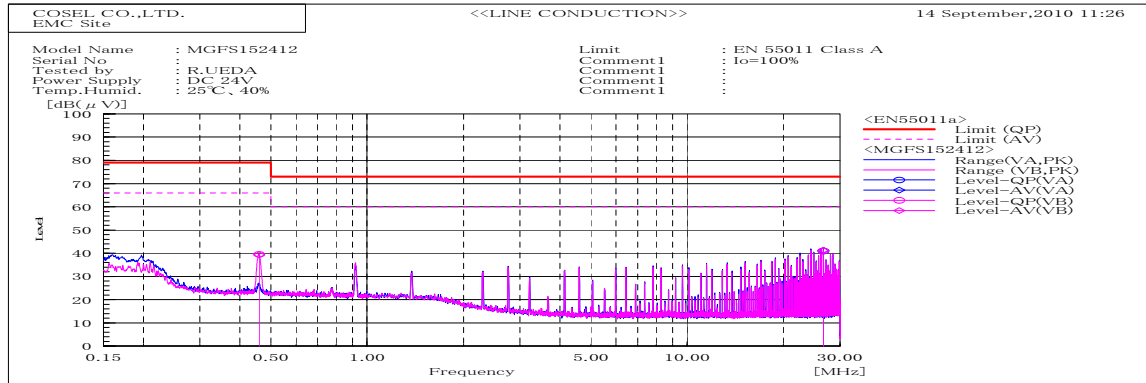
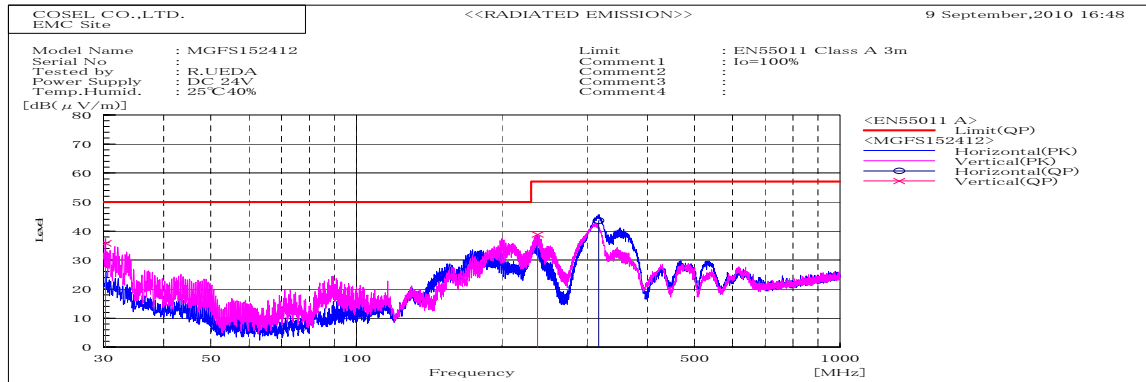


DATA SHEET		Date	21-Sep-10
Model	MGFS152412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46003		VB	29.5	29.3	10	39.5	39.3	79	66	39.5	26.7	Pass	
26.63675		VA	30.1	30.5	10.8	40.9	41.3	73	60	32.1	18.7	Pass	
26.6398		VB	29.9	30.3	11	40.9	41.3	73	60	32.1	18.7	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
30.305	V	Stable	49.4	-13.6		35.8		50	14.2	Pass	103	0	
237.08	V	Stable	57.7	-18.9		38.8		57	18.2	Pass	117	248	
316.786	H	Stable	60.8	-17.2		43.6		57	13.4	Pass	104	359	

# DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

## 1. Line conduction



## 2. Radiated emission

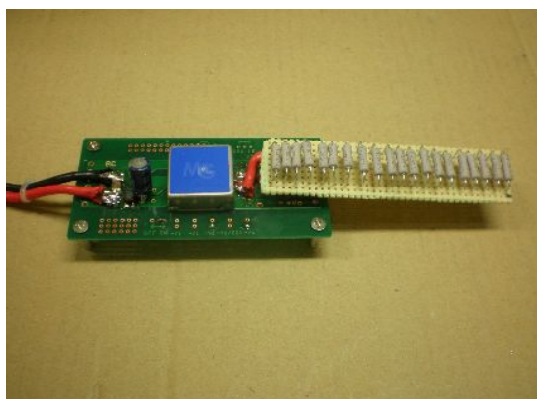


## Conditions

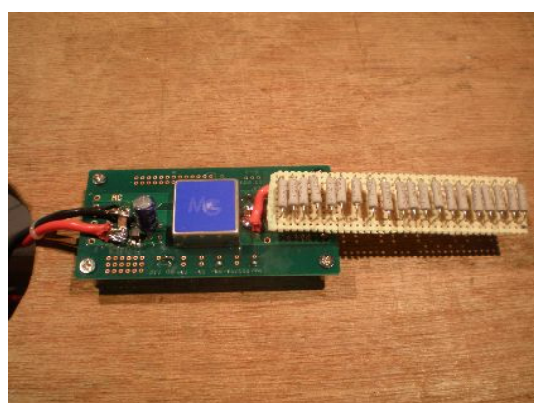
Test : EMI  
Model Name : MGFS1524□□/MGFW1524□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

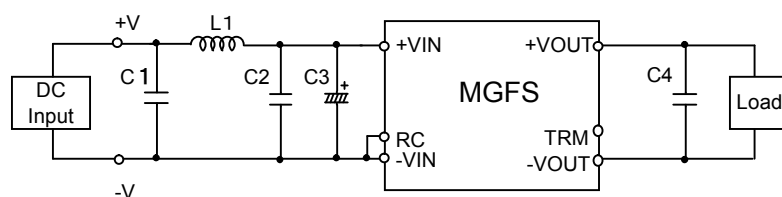


Fig.1 Testing circuitry 1

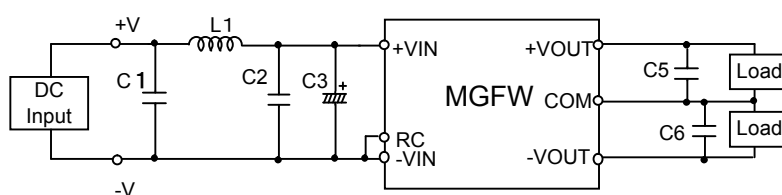


Fig.2 Testing circuitry 2

L1	: 0.5uH	CI4C-0R5	(KORIN ELECTRONICS)
C1,C2	: 50V 6.8 $\mu$ F	C4532X7R1H685MT	(TDK)
C3	: 50V 100 $\mu$ F	LXZ50VB100M	(NIPPON CHEMI-CON)
C4,C5,C6	: 25V 22 $\mu$ F	CM32X5R226K25A	(KYOCERA)